

REMARKS

This application contains claims 1 through 18. Claims 17 and 18 are newly added.

The present application was originally drafted in German, and then translated into English. In the present amendment, Applicants amended the claims to remove multiple dependencies, to conform to US drafting style, and to delete extraneous language. Applicants have not limited the scope of any term in any claim, and thus, Applicants respectfully submit that the doctrine of equivalents is available for all terms of all of the claims. Favorable consideration is respectfully urged.

Respectfully submitted,

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IN THE CLAIMS

1. (Amended) Illumination-An illumination system, particularly for lithography with wavelengths of ≤ 193 nm comprising:

1.1-a first optical element, which is divided into first raster elements and lies in a first plane, whereby

wherein said first plane defines an x-direction and an a y-direction, whereby

1.2 the images of the first raster elements superimpose in an object plane of the illumination system and

1.4 thewherein said first raster elements each have an x-direction and a y-direction with aan aspect ratio, and

characterized in that

1.5 wherein at least two of said first raster elements each have aaspect ratioratios of different magnitude.

2. (Amended) The illumination Illumination system according to claim 1, further characterized in that

the illumination system comprises further comprising a second optical element, which is divided into second raster elements, whereby

wherein a second raster element is assigned to a first raster element, and whereby

wherein at least one second raster element has an anamorphotic optical effect.

3. (Amended) The illumination Illumination system according to claim 2, further characterized in thatwherein the illumination system defines

a field with a field aspect ratio,

wherein said field is illuminated in thean object plane of the illumination system, and

wherein at least some of thesaid second raster elements have an anamorphotic

optical effect, which is selected such that thean aspect ratio of the images of thesaid first raster elements is substantially the same in thesaid object plane, independent of thesaid aspect ratio of thesaid first raster elements.

4. (Amended) The illumination Illumination system according to one of claims 1 to 3
claim 1,

further characterized in thatwherein
at least one of the said at least two first raster elements with aspect ratios of different magnitude has an anamorphotic optical effect.

5. (Amended) The illumination Illumination system according to one of claims 1 to 3
claim 1,

further characterized in thatwherein
the said at least two first raster elements with aspect ratios of different magnitude have an isotropic optical effect.

6. (Amended) The illumination Illumination system according to claim 5,
further characterized in thatwherein
the said first raster elements have an isotropic optical effect.

7. (Amended) The illumination Illumination system according to one of claims 1 to 5
claim 1,

further characterized in thatwherein
these said first raster elements that have an anamorphotic optical effect are of a shape selected from the group consisting of cylinders and/or toroids.

8. (Amended) The illumination Illumination system according to one of claims 1 to 7
claim 2,

further characterized in thatwherein
these said second raster elements that have an anamorphotic optical effect are of a shape selected from the group consisting of cylinders and/or toroids.

9. (Amended) The illumination Illumination system according to one of claims 1 to 8
claim 1,

~~further characterized in that wherein~~
~~all of the said first raster elements are completely illuminated in the said first plane.~~

10. (Amended) The illumination Illumination system according to one of claims 1 to 9
claim 1,

~~further characterized in that~~
~~the illumination system has~~further comprising a collector unit, which illuminates
~~the said first plane with the said first raster elements.~~

11. (Amended) The illumination Illumination system according to one of claims 1 to 10
claim 1,

~~further characterized in that~~
~~the illumination system has~~further comprising at least one field mirror.

12. (Amended) The illumination Illumination system according to claim 112,
further comprising at least one field mirror,
~~further characterized in that~~
~~wherein~~
~~the said second raster elements and the said at least one field mirror image the said~~
~~assigned first raster elements in the an object plane of the illumination system.~~

13. (Amended) The illumination Illumination system according to one of claims 1 to 12
claim 1,

~~further characterized in that~~
~~wherein~~
~~the said first raster elements are rectangular.~~

14. (Amended) The illumination Illumination system according to one of claims 1 to 13
claim 1,

~~further characterized in that~~
~~wherein the illumination system defines~~
~~the a field to be illuminated in the an object plane of the illumination system-, and~~
~~wherein said field represents a segment of a ring field.~~

15. (Amended) Projection A projection exposure system for microlithography with comprising:

- 15.1 an illumination system according to ~~one of claims 1 to 14~~claim 1 with an exit pupil-(112), which partially collects ~~the~~an emission produced by a light source (100) and further guides it to illuminate a field in ~~the~~an object plane of the Illumination illumination system;
- 15.2 a pattern-bearing mask, which lies in ~~the~~said object plane-(114) of the Illumination system;
- 15.3 a projection device, ~~particularly~~ a projection objective-(126) with an entrance pupil, which coincides with ~~the~~an exit pupil-(112) of the Illumination illumination system, whereby ~~this~~wherein said projection objective device images ~~the~~a lighted portion of ~~the~~said pattern-bearing mask in an image field of ~~the~~said projection device; and
- 15.4 a light-sensitive substrate-(124), which lies in ~~the~~a plane of ~~the~~said image field of ~~the~~projection device.

16. (Amended) Method A method for producing microelectronic microelectronic components, ~~particularly~~ semiconductor chips with comprising using the projection exposure system according to claim 15.

Claims 17 and 18 are newly added.